Anti Head in Pillow Defect



PF305 - 153TO^{Alloy Composition : Sn-3.0Ag-0.5Cu} Flux : Halogen Free, ROL0 in IPC standards

How head in pillow defect occurs in BGA package?



Schematic diagram of head in pillow defect caused by warpage in the package

Strong wettable durability inhibits head in pillow defect

We checked quantification of wettability with an exclusive apparatus to measure wetting force and wetting speed.



Mask : 0.2mmΦ and 0.12mmT

· Air reflowing

• Preheating 100sec at 180 to 190℃

· Peak temp. 240℃, 26sec for 220℃

Inhibiting heat slump and solder ball occurrence

Excellent depression effect for heat slump



Excellent depression effect for solder ball occurrence

Heating just after printing





[Test condition] Test method : JIS Z 3284 Printing pattern : ϕ =6.5mm, 0.2mmT mask thickness Substrate : Ceramic board (50mm×50mm×0.8mm) Heating condition : $150^{\circ}C60sec. \rightarrow 260^{\circ}C30sec.$ on hotplate

Recommended heating profile



Characteristics

Items		Representative value		Test method
Alloy composition		Sn-3.0Ag-0.5Cu		-
Particle size		IPC Type.4	IPC Type.5	-
Flux content		11.5 wt%	12.0 wt%	JIS Z 3197
Fluid characteristics	Viscosity	200 Pa • s		JIS Z 3284
	TI value	0.60		
Halide content		0.02%		JIS Z 3197
Flux type		ROL0		IPC J-STD-004
Tack time at 100gf or more		24 hours		JIS Z 3284

*The above values are not guranteed figures but represetative ones.

